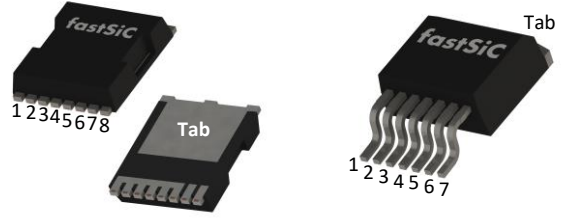
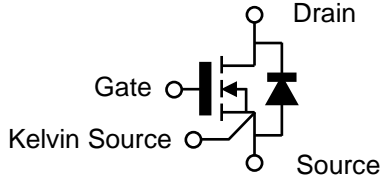


Silicon Carbide MOSFET
650V, 20mΩ SiC MOSFET – Falcon Series



Product Information:



Features

- Optimized $R_{DS(on)}$ with Rapid Switching Behavior
- Compatible with Standard Gate Drivers
- Clean Kelvin-Source Switching Pin-out
- High Avalanche Endurance Capability
- Optimized for High Power Density Applications
- RoHS Compliant and Halogen Free

Terminal	Packaging Type	
	TOLL	TO-263-7L
Gate	1	1
Drain	Tab	Tab
Source	3, 4, 5, 6, 7, 8	3, 4, 5, 6, 7
Kelvin Source	2	2

Benefits

- Higher System Efficiency
- Increase Parallel Device Convenience
- Enable High Temperature Application
- Allow High Frequency Operation
- Realize Compact and Lightweight Systems
- High Reliability

Potential Applications

- Switching Mode Power Supply
- PFC & DC/DC Converter
- EV Charging Station
- UPS
- Renewable Energy
- Power Inverter & Motor Driver

Key Performance Parameters

Parameter	Symbol	Value	Unit
Drain-Source Voltage	$V_{DS @ T_{j(max)}}$	700	V
Recommended Gate-Source Turn-On Voltage	V_{GS}	15~18	
Drain-Source On-State Resistance	$R_{DS(on)}$	22	mΩ
Continuous Drain Current	I_D	101	A
Pulse Drain Current	$I_{D, pulse}$	409	
Power Dissipation	P_{tot}	333	W
Avalanche Energy	E_{AS}	1500	mJ
Gate Charge	Q_G	194	nC
Output Capacitive Charge	Q_{oss}	188	
Junction & Storage Temperature	T_j, T_{stg}	-55 to 175	°C

Part Number	Package	Marking
FF06020FA	TOLL	FF06020A
FF06020J-7A	TO-263-7L	FF06020A
--	--	--

For further information about comparable products, please contact (www.fastsic.com).

Maximum Ratings: ($T_j = 25^\circ\text{C}$, unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Drain-Source Voltage	V_{DSS}	650	--	--	V	$V_{GS}=0\text{V}, I_D=100\mu\text{A}$
Continuous Drain Current	I_D	--	--	101 73	A	$V_{GS}=18\text{V}, T_c=25^\circ\text{C}$ $V_{GS}=18\text{V}, T_c=100^\circ\text{C}$
Pulse Drain Current	$I_{D,pulse}$	--	--	409		Per Fig. 13
Continuous Body Diode Current	I_S	--	--	59		$V_{GS}=0\text{V}, T_c=25^\circ\text{C}$
Avalanche Energy, Single Pulse	E_{AS}	--	--	1500	mJ	$L=25\text{mH}$
Operate Gate Source Voltage	$V_{GS,op}$	-8~0	--	15~18	V	Recommended operating values
Transient Gate Source Voltage	$V_{GS,tran.}$	-10	--	22		Transient operating limit (AC $f > 1\text{Hz}$, pulse width $< 100\text{ns}$)
Power Dissipation	P_{tot}	--	--	333	W	$T_c=25^\circ\text{C}$
Junction Temperature	T_j	-55	--	175	°C	--
Storage Temperature	T_{stg}	-55	--	175		
Soldering Temperature	T_L	--	--	260		

Electrical Characteristics:

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
DC Characteristics (at $T_j = 25^\circ\text{C}$, unless otherwise specified)						
Drain-source Breakdown Voltage	$V_{(BR)DSS}$	650	-- 700	--	V	$V_{GS}=0\text{V}, I_D=100\mu\text{A}, T_j=25^\circ\text{C}$ $V_{GS}=0\text{V}, I_D=100\mu\text{A}, T_j=175^\circ\text{C}$
Drain-Source On-State Resistance	$R_{DS(on)}$	--	22 29	28	mΩ	$V_{GS}=18\text{V}, I_D=35\text{A}, T_j=25^\circ\text{C}$ $V_{GS}=18\text{V}, I_D=35\text{A}, T_j=175^\circ\text{C}$
Gate-Source Threshold Voltage	V_{th}	--	2.5	--	V	$V_{GS}=V_{DS}, I_D=60\text{mA}$
Zero Gate Voltage Drain Current	I_{DSS}	--	4	60	μA	$V_{DS}=650\text{V}, V_{GS}=0\text{V}, T_j=25^\circ\text{C}$
Gate-Source Leakage Current	I_{GSS}	--	--	100	nA	$V_{GS}=18\text{V}, V_{DS}=0\text{V}$
Body Diode Forward Voltage	V_{SD}	--	3.3 2.9	--	V	$V_{GS}=0\text{V}, I_S=20\text{A}, T_j=25^\circ\text{C}$ $V_{GS}=0\text{V}, I_S=20\text{A}, T_j=175^\circ\text{C}$
AC Characteristics (at $T_j = 25^\circ\text{C}$, unless otherwise specified)						
Input Capacitance	C_{iss}	--	4437	--	pF	$V_{DS}=400\text{V}, V_{GS}=0\text{V},$ $f=250\text{kHz}, V_{AC}=25\text{mV}$
Output Capacitance	C_{oss}	--	322	--		
Reverse Capacitance	C_{rss}	--	50	--		
Effective Output Capacitance, energy related	$C_{o(er)}^1$	--	354	--		
Effective Output Capacitance, time related	$C_{o(tr)}^2$	--	470	--		
C_{oss} Stored Energy	E_{oss}	--	28	--		
Output Capacitive Charge	Q_{oss}	--	188	--	nC	
Internal Gate Resistance	$R_{G,int.}$	--	1.5	--	Ω	$f=1\text{MHz}, V_{AC}=25\text{mV}$

¹ $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 400V.

² $C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 400V.

Switching Characteristics:

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Gate Characteristics						
Gate to Source Charge	Q_{GS}	--	31	--	nC	$V_{DS}=400V, V_{GS}=0V/15V, I_D=35A$
Gate to Drain Charge	Q_{GD}	--	82	--		
Total Gate Charge	Q_G	--	194	--		
Inductive Load						
Turn On Delay Time	$t_{d(on)}$	--	88	--	ns	$V_{DS}=400V,$ $I_D=45A,$ $V_{GS}=-3/+15V,$ $R_{G_{on, ext.}} = 2.7\Omega, R_{G_{off, ext.}} = 1\Omega$ External SiC Diode as an FWD
Rise Time	t_r	--	52	--		
Turn Off Delay Time	$t_{d(off)}$	--	40	--		
Fall Time	t_f	--	15	--		
Turn On Switching Energy	E_{on}	--	1172	--	μJ	
Turn Off Switching Energy	E_{off}	--	137	--		
Resistive Load						
Turn On Delay Time	$t_{d(on)}$	--	30	--	ns	$V_{DS}=400V,$ $I_D=40A, V_{GS}=-3/+15V,$ $R_L=10\Omega$
Rise Time	t_r	--	40	--		
Turn Off Delay Time	$t_{d(off)}$	--	41	--		
Fall Time	t_f	--	15	--		
Body Diode Characteristics						
Reverse Recovery Charge	Q_{rr}	--	299	--	nC	$V_{GS}=0V,$ $I_S=40A, V_{DS}=400V,$ $di/dt=1125A/\mu s$ * Q_{rr} herein excluded the Q_{oss} value.
Reverse Recovery Time	t_{rr}	--	34	--	ns	
Peak Reverse Recovery Current	I_{rrm}	--	17.6	--	A	

Thermal Characteristics:

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Thermal Impedance, junction-case	R_{th-jc}	--	0.45	--	K/W	--
Thermal Impedance, junction-ambient	R_{th-ja}	--	40	--		Device on PCB, with 6 cm ² of cooling area

Electrical Characteristics Diagrams

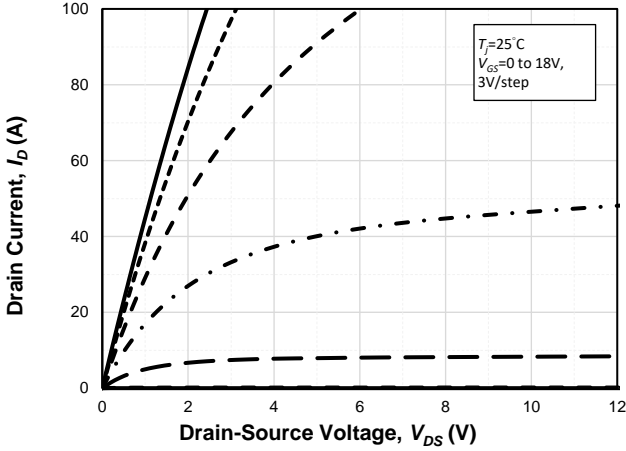


Fig. 1 Typical Output Characteristics at $T_j=25^\circ\text{C}$

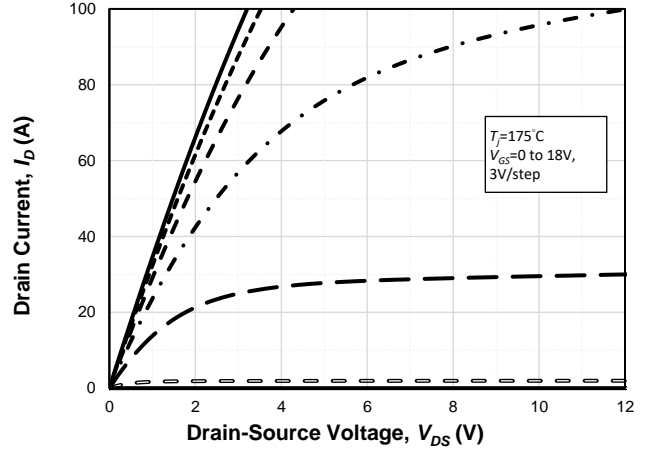


Fig. 2 Typical Output Characteristics at $T_j=175^\circ\text{C}$

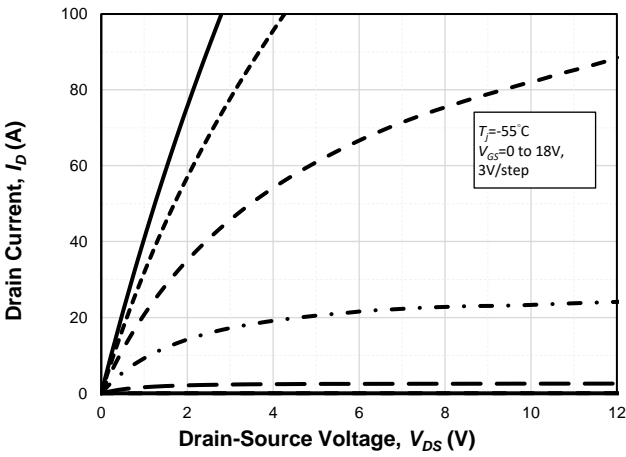


Fig. 3 Typical Output Characteristics at $T_j=-55^\circ\text{C}$

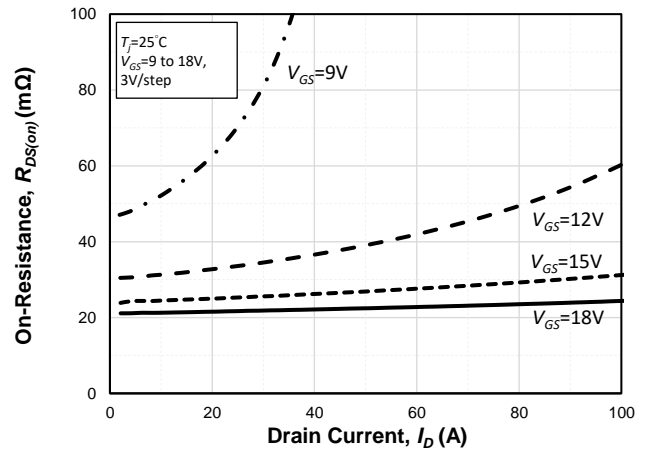


Fig. 4 Typ. $R_{DS(on)}$ vs. I_D with Various V_{GS}

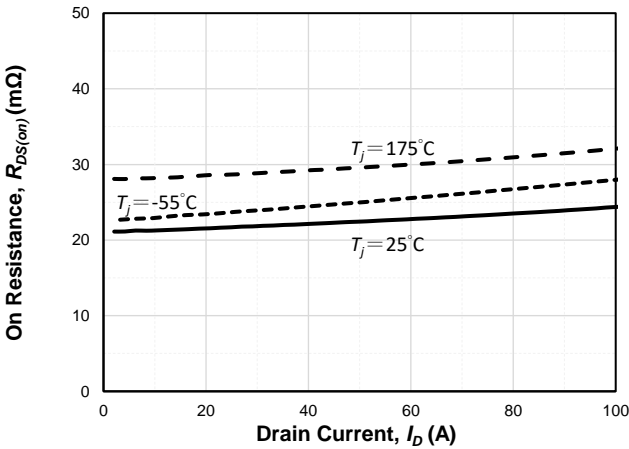


Fig. 5 Typ. $R_{DS(on)}$ vs. I_D with Various T_j , $V_{GS}=18\text{V}$

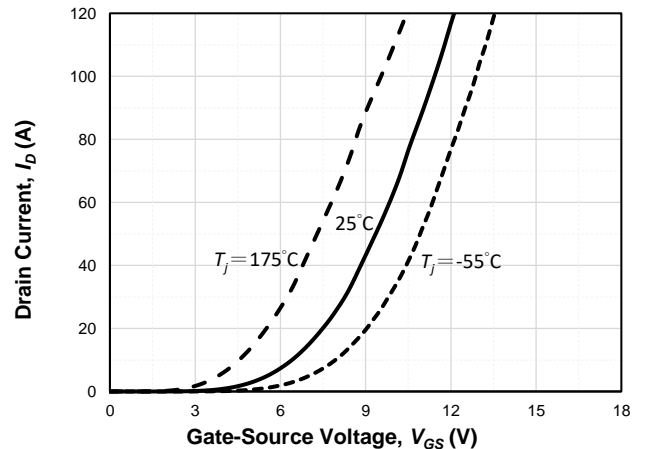


Fig. 6 Typ. I_D vs. V_{GS} with Various T_j , $V_{DS}=10\text{V}$

Electrical Characteristics Diagrams

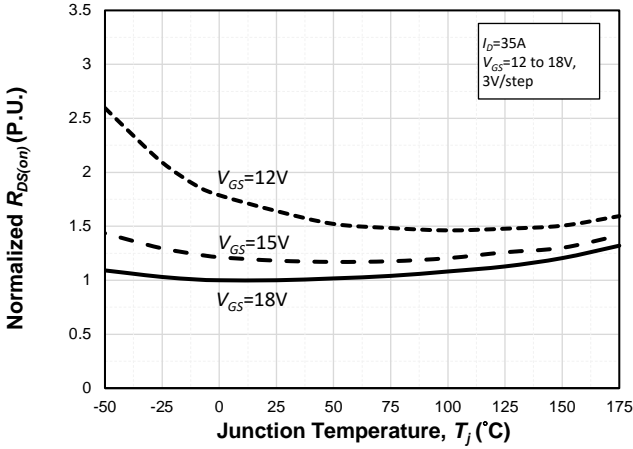


Fig. 7 Normalized $R_{DS(on)}$ vs. T_j with Various V_{GS}

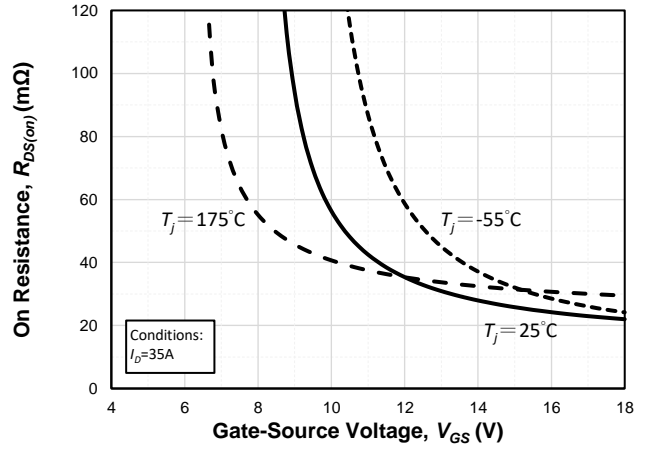


Fig. 8 Typ. $R_{DS(on)}$ vs. V_{GS} with Various T_j

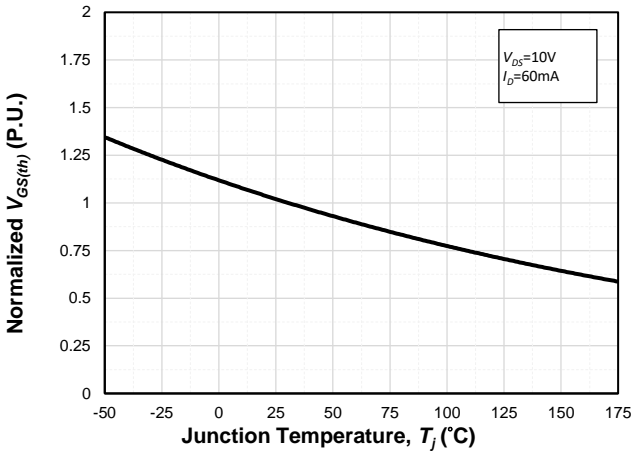


Fig. 9 Normalized V_{th} vs. T_j

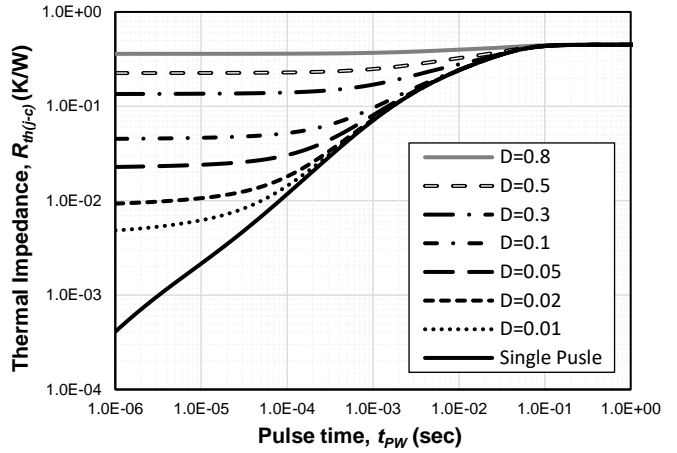


Fig. 10 Typ. Transient Thermal Impedance R_{th-jc}

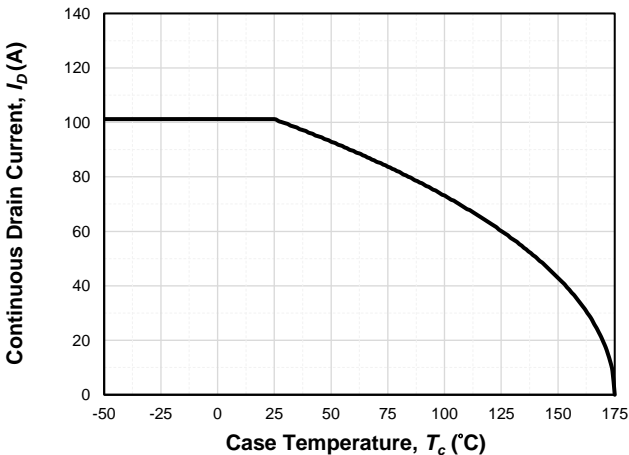


Fig. 11 Continuous I_D De-rating at $V_{GS}=18V$, $T_j \leq 175^\circ C$

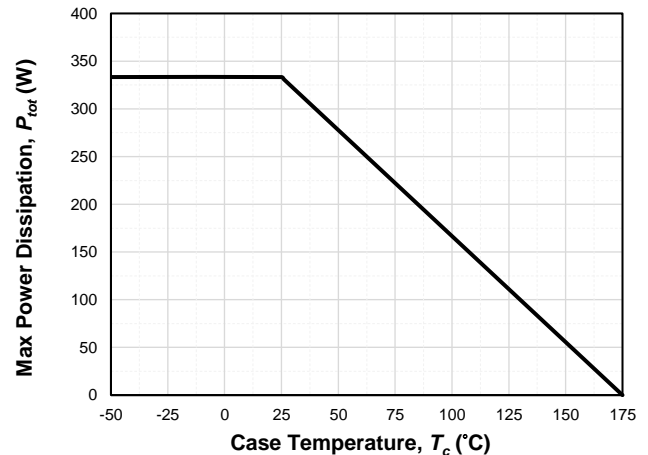


Fig. 12 Power Dissipation at $V_{GS}=18V$, $T_j \leq 175^\circ C$

Electrical Characteristics Diagrams

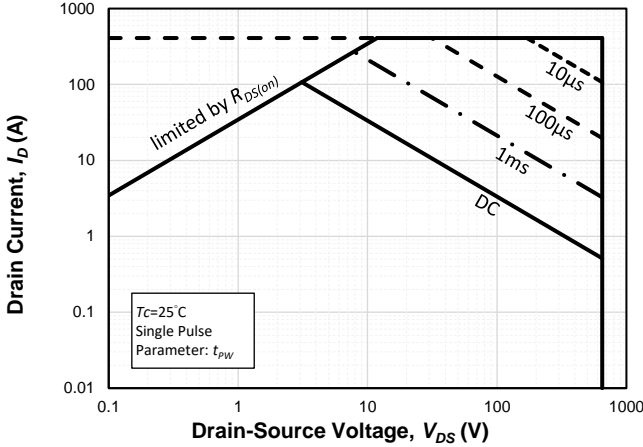


Fig. 13 Safe Operating Area at $T_c=25^\circ\text{C}$

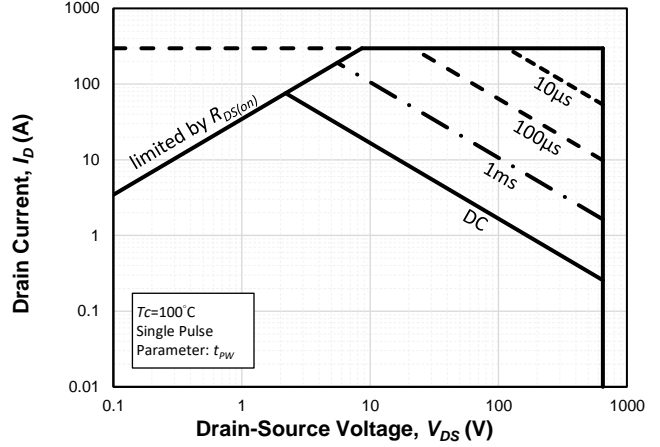


Fig. 14 Safe Operating Area at $T_c=100^\circ\text{C}$

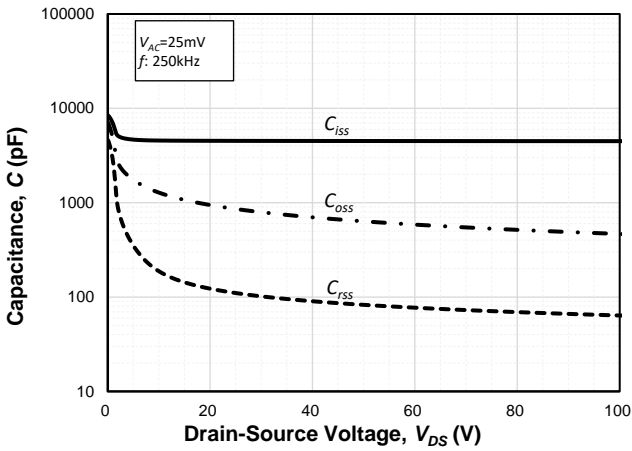


Fig. 15 Typ. Capacitance vs. V_{DS} at $f_{sw}=250\text{kHz}$, $V_{DS}\leq 100\text{V}$

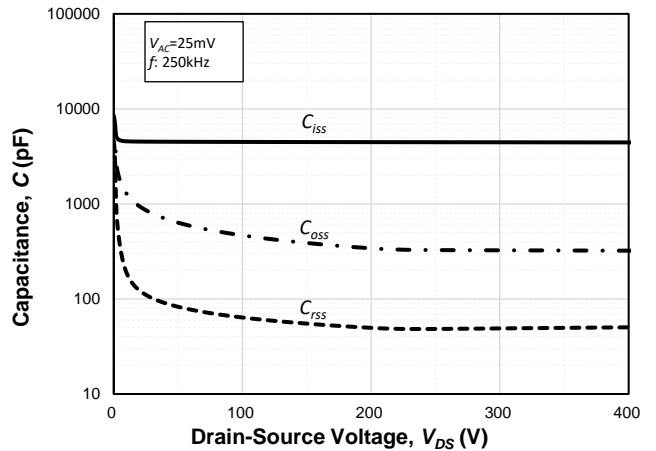


Fig. 16 Typ. Capacitance vs. V_{DS} at $f_{sw}=250\text{kHz}$, $V_{DS}\leq 400\text{V}$

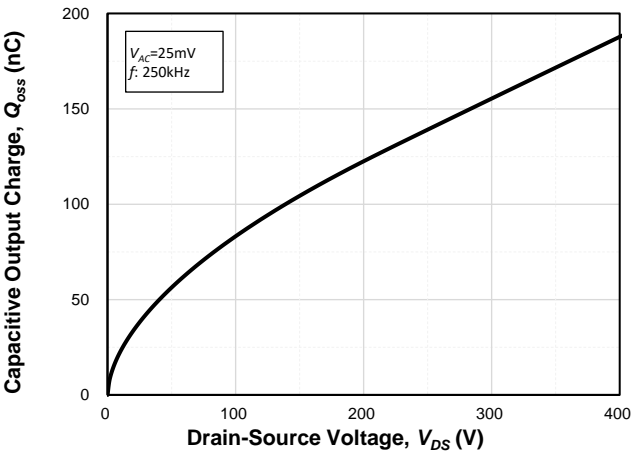


Fig. 17 Typ. Capacitive Output Charge at $f_{sw}=250\text{kHz}$

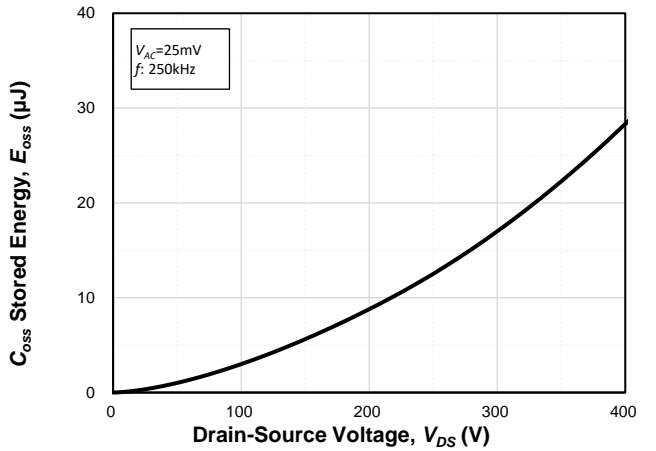


Fig. 18 Typ. C_{oss} Stored Energy at $f_{sw}=250\text{kHz}$

Electrical Characteristics Diagrams

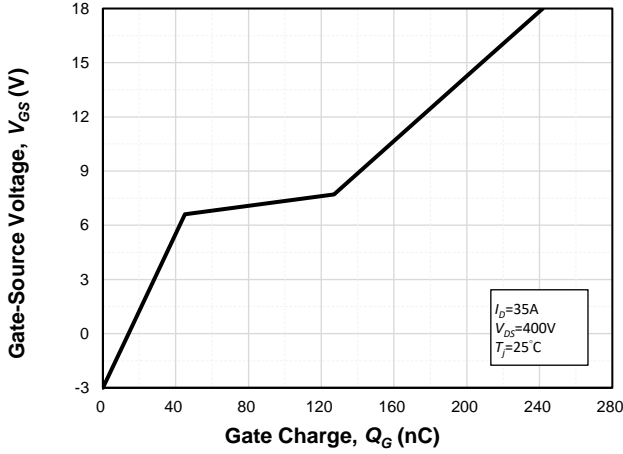


Fig. 19 Typ. Gate Charge at $V_{DS}=400V$, $I_D=40A$

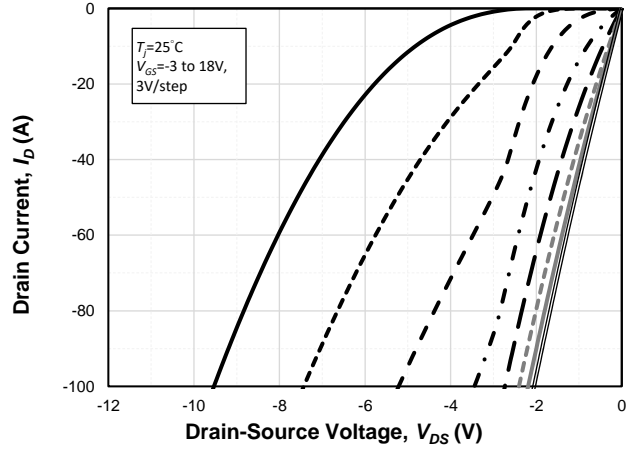


Fig. 20 Typical Forward Characteristics of Reverse Conduction at $T_J=25^\circ C$

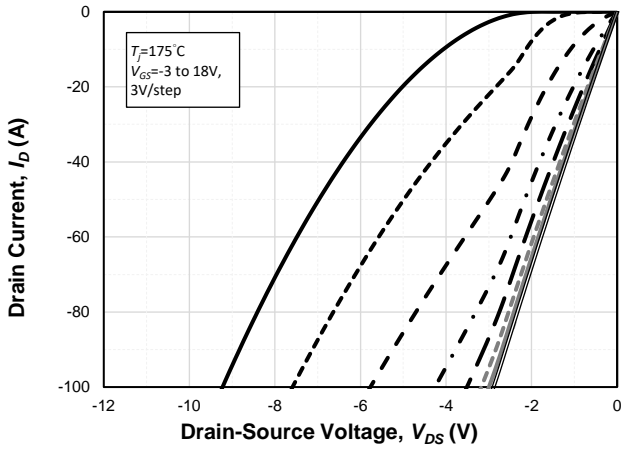


Fig. 21 Typical Forward Characteristics of Reverse Conduction at $T_J=175^\circ C$

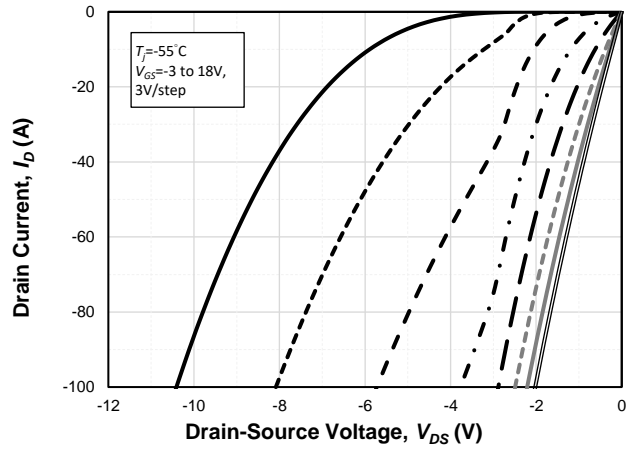


Fig. 22 Typical Forward Characteristics of Reverse Conduction at $T_J=-55^\circ C$

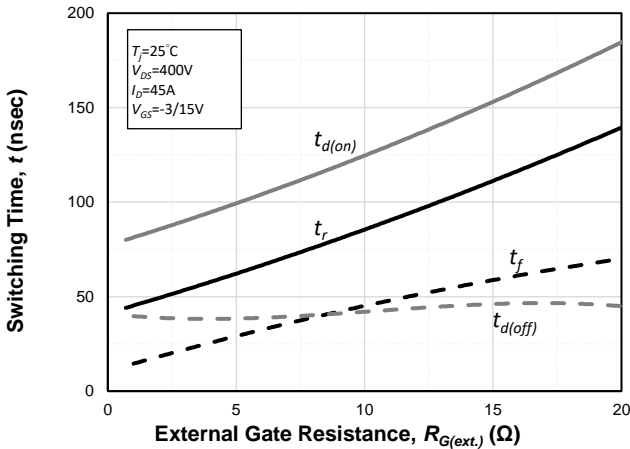


Fig. 23 Typ. Switching Time vs. $R_{G(ext.)}$

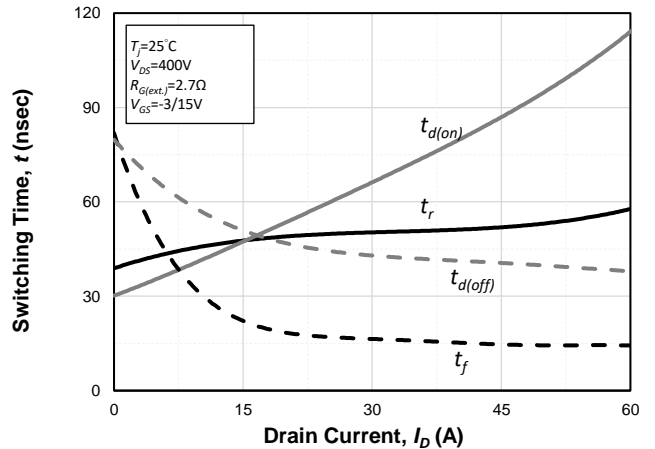


Fig. 24 Typ. Switching Time vs. I_D

Electrical Characteristics Diagrams

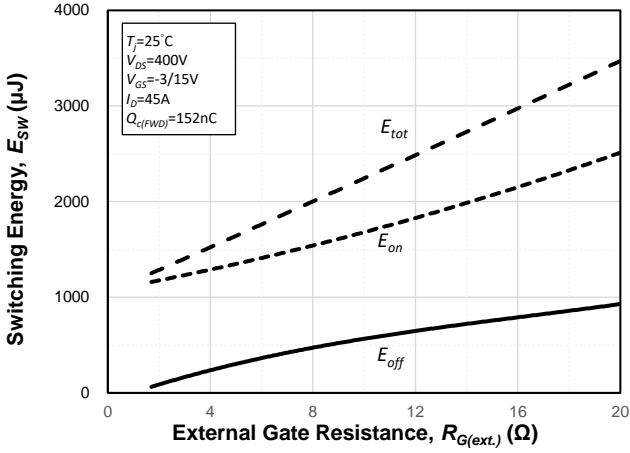


Fig. 25 Typ. Switching Energy vs. $R_{G(ext.)}$

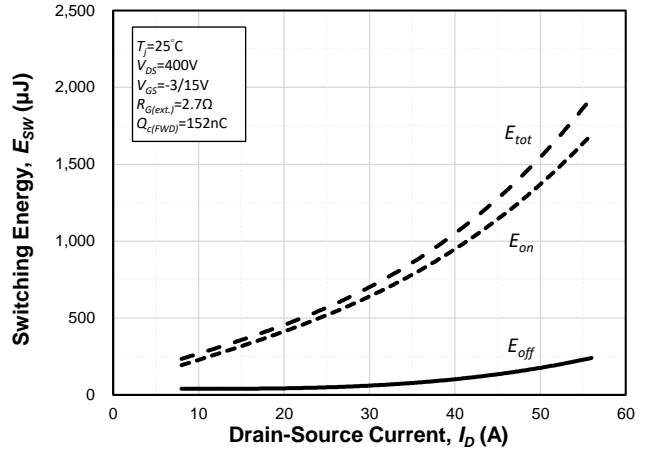
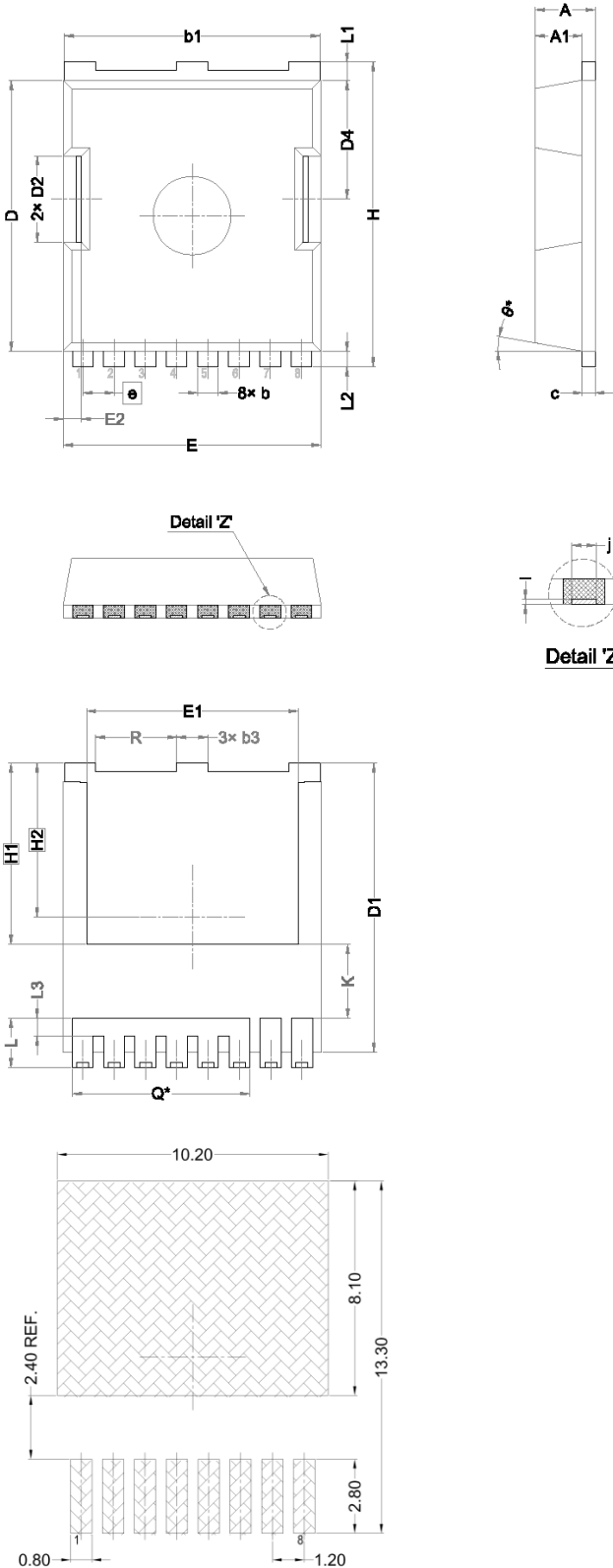


Fig. 26 Typ. Switching Energy vs. I_D

Package Outline (TOLL, MO-299B)



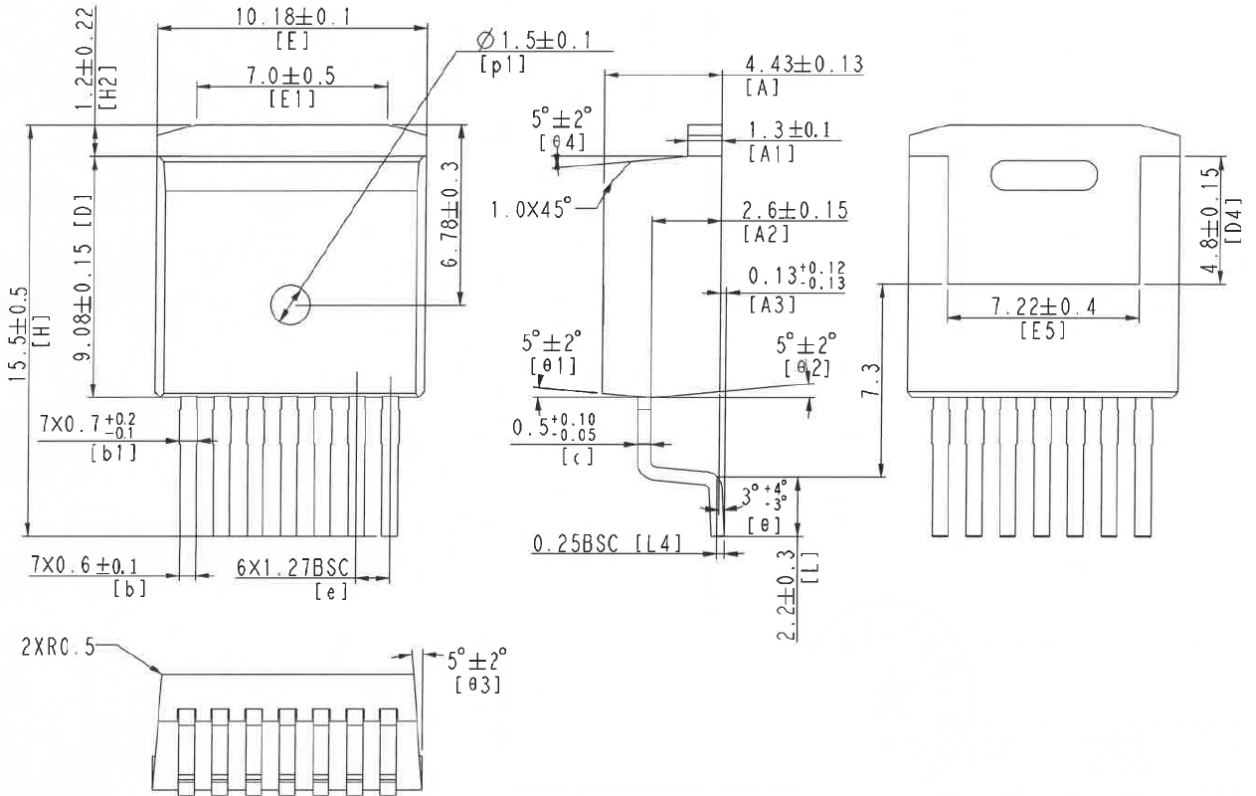
Symbol	Dimension (Millimeters)		
	Min.	Nom.	Max.
A	2.20	2.30	2.40
A1	1.70	1.80	1.90
b	0.70	0.80	0.90
b1	9.70	9.80	9.90
b3	1.10	1.20	1.30
c	0.40	0.50	0.60
D	10.28	10.38	10.48
D1	10.98	11.08	11.18
D2	3.20	3.30	3.40
D4	4.45	4.55	4.65
E	9.80	9.90	10.00
E1	8.00	8.10	8.20
E2	0.60	0.70	0.80
e	1.20 BSC.		
H	11.58	11.68	11.78
H1	6.95 BSC.		
H2	5.89 BSC.		
i	0.10 REF.		
j	0.46 REF.		
K	2.80 REF.		
L	1.40	1.90	2.10
L1	0.60	0.70	0.80
L2	0.50	0.60	0.70
L3	0.30	0.70	0.80
N	8		
Q	6.80 REF.		
R	3.00	3.10	3.20
θ	10° REF.		

Note:

1. Dimensions do not inclusive burrs and mold flash.
2. "*" is for reference.

Land Pattern (Only for reference)

Package Outline (TO-263-7L)



Revision History

Date	Revision	Changes
23.06	Tentative	1 st issue
23.09	Preliminary	Update electrical parameters and curves
24.05	Preliminary	Update diode recovery characteristics
24.11	Preliminary	Update pad layout

Important Note (Disclaimer)

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